# **Power MOSFET**

40 V, 74 A, 9.3 m $\Omega$ 

### **Features**

- Low R<sub>DS(on)</sub>
- Low Capacitance
- Optimized Gate Charge
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Parameter		Symbol	Value	Unit		
Drain-to-Source Voltage			$V_{DSS}$	40	V	
Gate-to-Source Voltage			$V_{GS}$	±20	V	
Continuous Drain Current R <sub>0.1A</sub>		T <sub>A</sub> = 25°C	I <sub>D</sub>	13	Α	
(Note 1)	Steady State	T <sub>A</sub> = 100°C		11		
Power Dissipation		T <sub>A</sub> = 25°C	$P_{D}$	3.0	W	
R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 100°C		1.9		
Continuous Drain Current R <sub>BJC</sub>		T <sub>C</sub> = 25°C	I <sub>D</sub>	74	Α	
(Note 1)		T <sub>C</sub> = 100°C		59		
Power Dissipation		T <sub>C</sub> = 25°C	P <sub>D</sub>	89	W	
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		57		
Pulsed Drain Current	t <sub>p</sub> = 10 μs		I <sub>DM</sub>	276	Α	
Operating Junction and Storage Temperature		$T_J$ , $T_{STG}$	-55 to +150	°C		
Source Current (Body Diode)			I <sub>S</sub>	74	Α	
Single Pulse Drain-to-Source Avalanche Energy (L = 0.1 mH)		EAS	48	mJ		
		IAS	31	Α		
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C		

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Bottom) (Note 1)	$R_{\theta JC}$	1.4	
Junction-to-Case (Top) (Note 1)	$R_{\theta JC}$	4.5	
Junction-to-Ambient Steady State (Note 1)	$R_{ heta JA}$	41	°C/W
Junction-to-Ambient Steady State (Note 2)	$R_{\theta JA}$	75	

- Surface-mounted on FR4 board using 1 sq-in pad
- (Cu area = 1.127 in sq [2 oz] including traces).

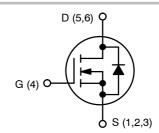
  2. Surface–mounted on FR4 board using 0.155 in sq (100mm²) pad size.



## ON Semiconductor®

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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
40 V	9.3 m $\Omega$ @ 10 V	74 A
	13.6 m $\Omega$ @ 4.5 V	74 A



**N-CHANNEL MOSFET** 



**MARKING DIAGRAM** D S D 5834L S AYWW= S

= Assembly Location

= Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS5834NLT1G	DFN5 (Pb-Free)	1500/Tape & Reel

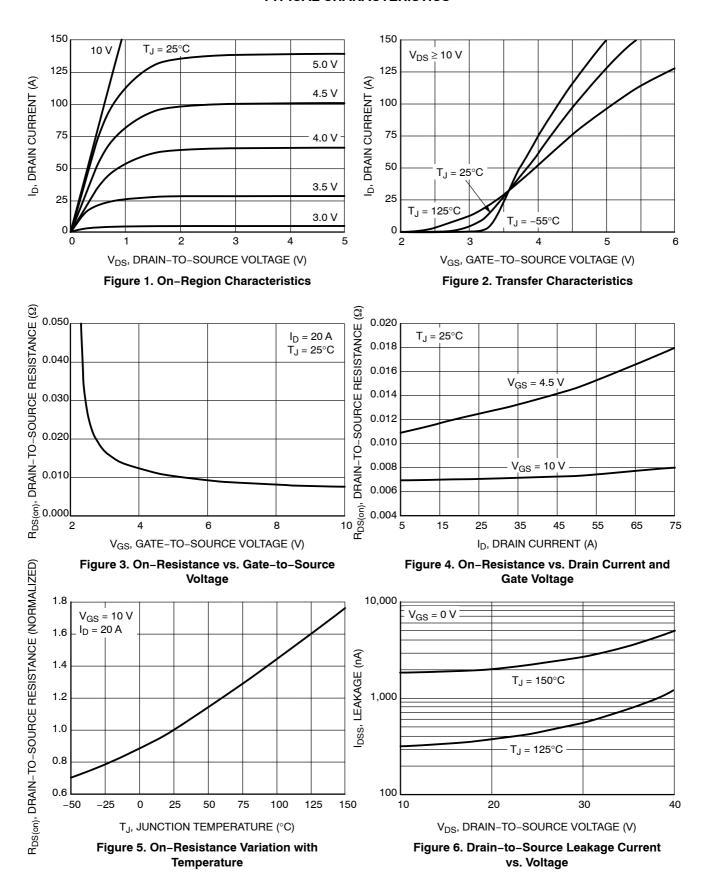
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu A$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				34.7		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 40 V	T <sub>J</sub> = 25 °C			1.0	μΑ
		V <sub>DS</sub> = 40 V	T <sub>J</sub> = 125°C			100	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)					•	•	•
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 250 \mu A$		1.0		3.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.7		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 20 A		7.1	9.3	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 20 A		11.3	13.6	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 20 A			29		S
CHARGES, CAPACITANCES & GATE RESIS	STANCE						•
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 20 V			1231		pF
Output Capacitance	C <sub>OSS</sub>				198		
Reverse Transfer Capacitance	C <sub>RSS</sub>				141		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 20 V; I <sub>D</sub> = 20 A			24		nC
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 20 V; I <sub>D</sub> = 20 A			12		
Threshold Gate Charge	Q <sub>G(TH)</sub>				1.0		
Gate-to-Source Charge	Q <sub>GS</sub>				4.2		
Gate-to-Drain Charge	$Q_{GD}$				6.3		1
Plateau Voltage	V <sub>GP</sub>				3.4		V
Gate Resistance	$R_{G}$				0.7		Ω
SWITCHING CHARACTERISTICS (Note 4)					•	•	•
Turn-On Delay Time	t <sub>d(ON)</sub>				10		
Rise Time	t <sub>r</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS}$	s = 20 V.		56.4		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 20 \text{ A}, R_G = 2.5 \Omega$			17.4		ns -
Fall Time	t <sub>f</sub>				6.6		
DRAIN-SOURCE DIODE CHARACTERISTIC	s				<u>-</u>	<u> </u>	
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 20 A	T <sub>J</sub> = 25°C		0.84	1.2	.,
			T <sub>J</sub> = 125°C		0.72		\ \
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 20 A			18		ns
Charge Time	ta				10		
Discharge Time	t <sub>b</sub>				8.0		
Reverse Recovery Charge	Q <sub>RR</sub>				108		nC

<sup>3.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.

### TYPICAL CHARACTERISTICS



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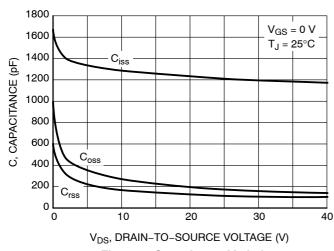


Figure 7. Capacitance Variation

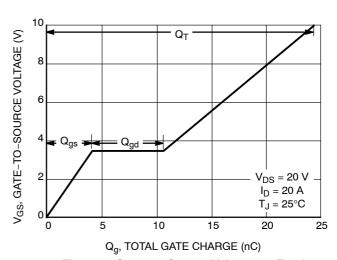


Figure 8. Gate-to-Source Voltage vs. Total Charge

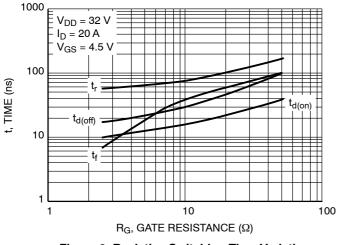


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

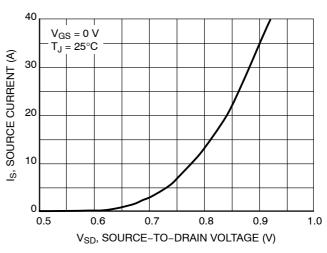


Figure 10. Diode Forward Voltage vs. Current

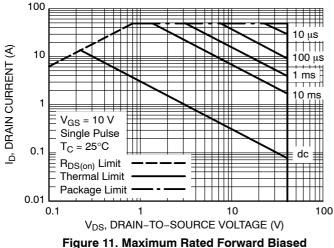


Figure 11. Maximum Rated Forward Biased Safe Operating Area

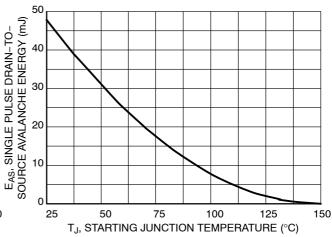


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

## **TYPICAL CHARACTERISTICS**

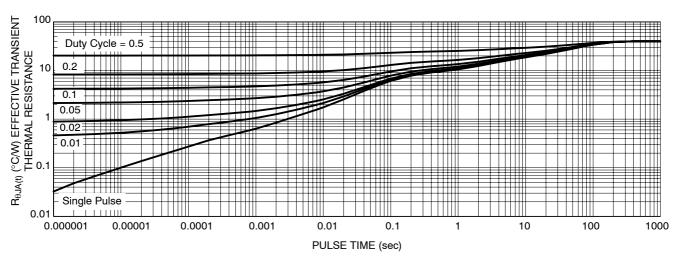
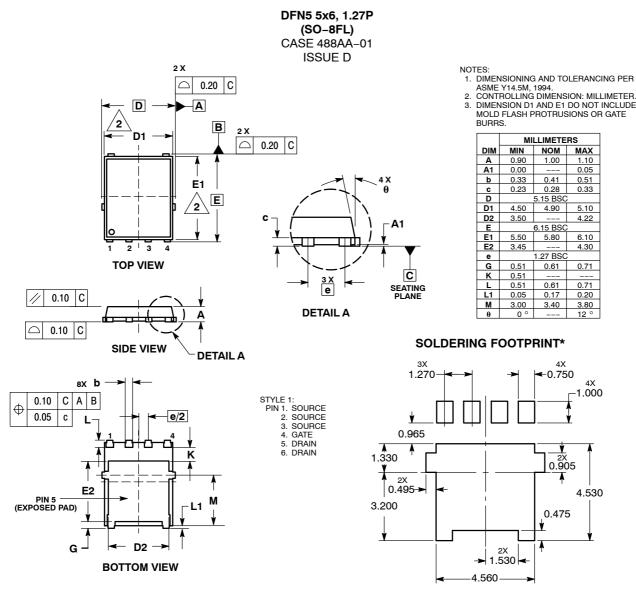


Figure 13. Thermal Response

#### PACKAGE DIMENSIONS



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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